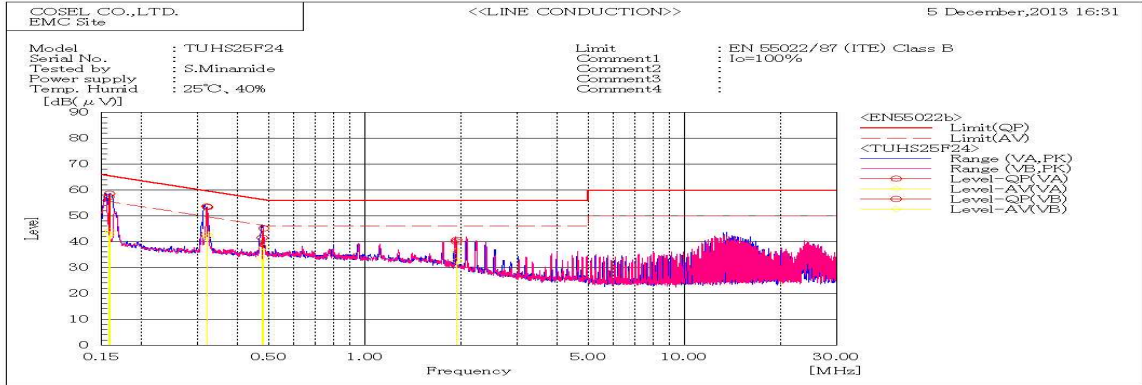
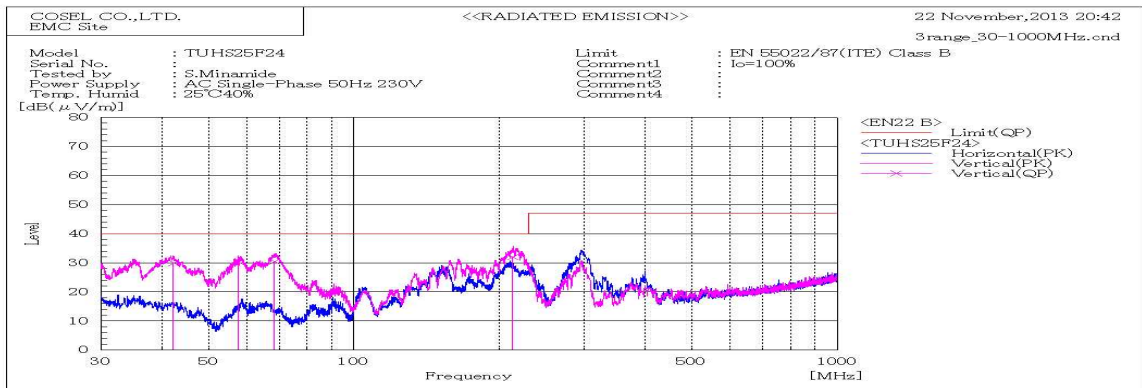


DATA SHEET		Date	16-Dec-13
Model	TUHS25F24	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide



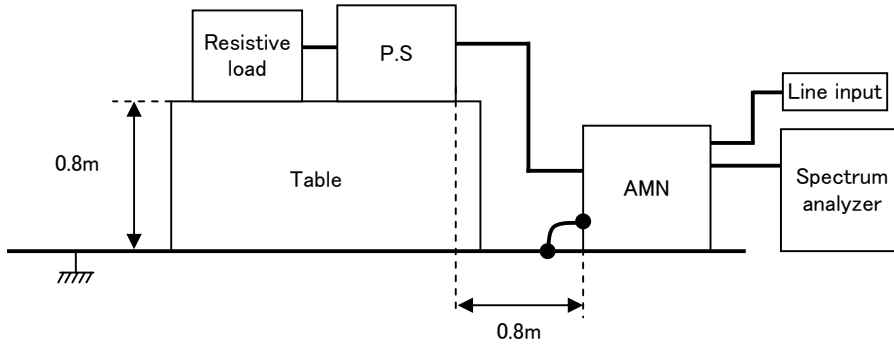
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.15841		VB	37.1	22.5	20.2	57.3	42.7	65.5	55.5	8.2	12.8	Pass	
0.15925		VA	38.4	23.9	20.2	58.6	44.1	65.5	55.5	6.9	11.4	Pass	
0.32071		VA	33.6	22.8	20.1	53.7	42.9	59.7	49.7	6	6.8	Pass	
0.32268		VB	33.3	21.7	20.1	53.4	41.8	59.6	49.6	6.2	7.8	Pass	
0.4781		VA	21.4	13.2	20.1	41.5	33.3	56.4	46.4	14.9	13.1	Pass	
0.48385		VB	25	17.7	20.1	45.1	37.8	56.3	46.3	11.2	8.5	Pass	
1.93618		VA	20.4	16.1	20.3	40.7	36.4	56	46	15.3	9.6	Pass	
1.93591		VB	19.7	12.3	20.3	40	32.6	56	46	16	13.4	Pass	



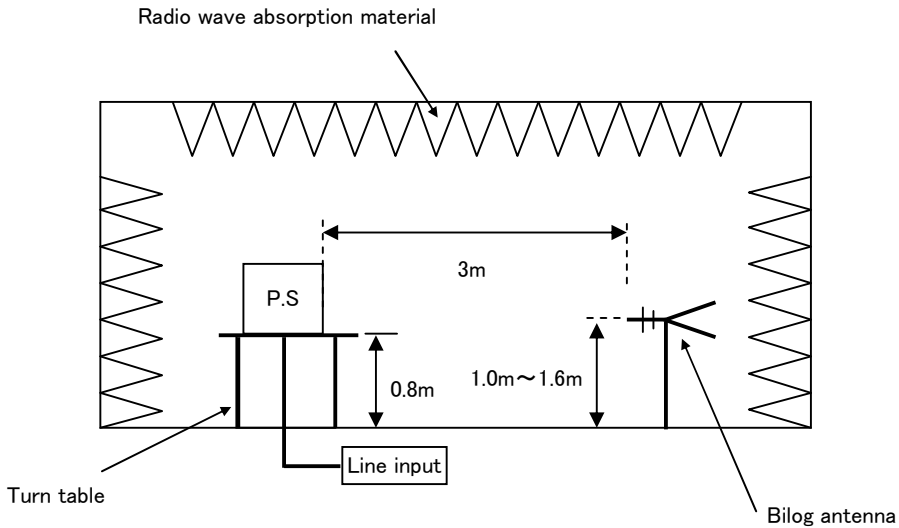
Frequency MHz	Polarization	Stability	Reading dB(uV)		Factor dB(1/m)	Level dB(uV/m)		Limit dB(uV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
42.326	V	Stable	46.4	-16.4		30	40	40	10	Pass	104	103	
57.697	V	Stable	54.3	-24		30.3	40	40	9.7	Pass	102	64	
68.522	V	Stable	51.3	-20.9		30.4	40	40	9.6	Pass	116	142	
213.298	V	Stable	46.9	-14.9		32	40	40	8	Pass	104	344	

DATA SHEET		Date	16-Dec-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide

1. Line conduction



2. Radiated emission



Conditions

Test: EMI
 Model Name: TUHS25F□□

- Photographs of Test Set-Up

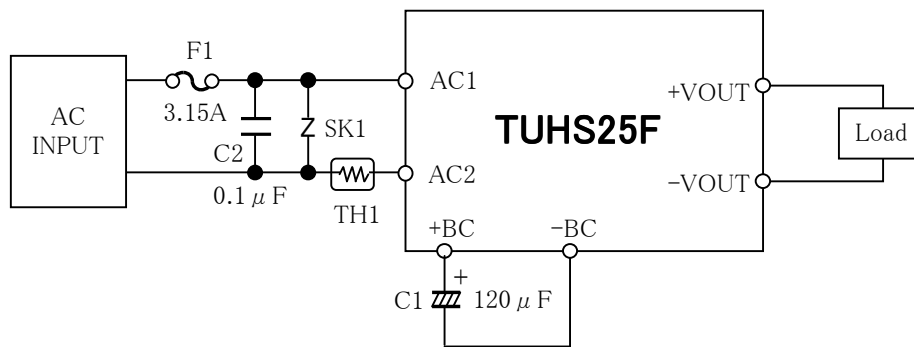
LINE CONDUCTION



RADIATED EMISSION



- Test circuit



F1:	SLT250V3.15A (Nippon Seisen)	3.15A
TH1:	10D2-08LCS (SEMITEC)	10Ω
SK1:	S10K385E2K1 (TDK EPCOS)	

Fig.1 Testing circuitry